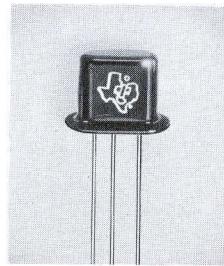




## N-P-N GROWN JUNCTION SILICON TRANSISTOR

9 to 20 beta spread

Specifically designed for high gain at high temperatures

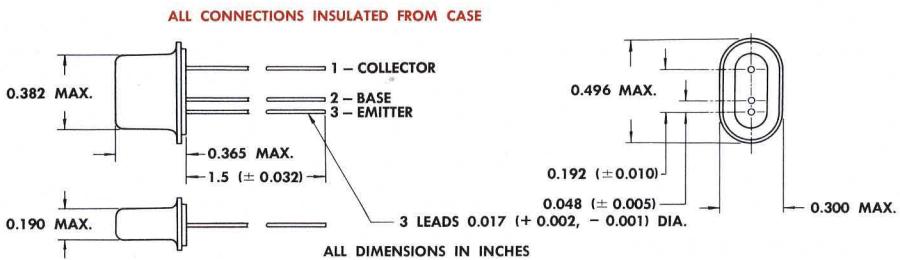


## qualification testing

All units are heat cycled from  $-65^{\circ}\text{C}$  to  $+175^{\circ}\text{C}$ . This test consists of fourteen cycles, four at 95% relative humidity (from  $-65^{\circ}\text{C}$  to  $+75^{\circ}\text{C}$ ). Also, the hermetic seal is checked by pressure testing. All units are completely tested for design characteristics and undergo a rigorous tumble test to check for mechanical reliability. These units are designed to meet the requirements of MIL-T-19500/35.

## mechanical data

Welded case with glass-to-metal hermetic seal between case and leads. Approximate weight is 1.7 grams.

absolute maximum ratings at  $25^{\circ}\text{C}$  ambient [except where advanced temperatures are indicated]

Collector Voltage Referred to Base . . . . .	45 V
Emitter Voltage Referred to Base . . . . .	1 V
Collector Current . . . . .	25 mA
Emitter Current . . . . .	-25 mA
Collector Dissipation } . . . . .	150 mW
at $100^{\circ}\text{C}$ . . . . .	100 mW
at $150^{\circ}\text{C}$ . . . . .	50 mW

## junction temperature

Maximum Range . . . . .  $-65^{\circ}\text{C}$  to  $+175^{\circ}\text{C}$

common base design characteristics at  $T_j = 25^{\circ}\text{C}$  [except where advanced temperatures are indicated]

	test conditions	min.	design center	max.	unit
$BV_{CBO}$	Collector Breakdown Voltage	$I_C = 50\mu\text{A}$	$I_E = 0$	45	—
$I_{CBO}$	Collector Cutoff Current } at $100^{\circ}\text{C}$ } at $150^{\circ}\text{C}$ }	$V_{CB} = 30\text{V}$	$I_E = 0$	—	2 $\mu\text{A}$
$h_{ib}$	Input Impedance	$V_{CB} = 5\text{V}$	$I_E = 0$	—	10 $\mu\text{A}$
$h_{ob}$	Output Admittance	$V_{CB} = 5\text{V}$	$I_E = 0$	50	$\mu\text{A}$
$h_{rb}$	Feedback Voltage Ratio	$V_{CB} = 5\text{V}$	$I_E = -1\text{mA}$	30	42
$h_{fb}$	Current Transfer Ratio	$V_{CB} = 5\text{V}$	$I_E = -1\text{mA}$	0.0	80
$PG_e$	Power Gain*†	$V_{CE} = 20\text{V}$	$I_E = -1\text{mA}$	25	0.4
$NF$	Noise Figure‡	$V_{CE} = 5\text{V}$	$I_E = -1\text{mA}$	120	1.2 $\mu\text{mho}$
$f_{\alpha b}$	Frequency Cutoff	$V_{CB} = 5\text{V}$	$I_E = -1\text{mA}$	-0.9	$X10^{-6}$
$C_{ob}$	Output Capacitance (1mc)	$V_{CB} = 5\text{V}$	$I_E = -1\text{mA}$	-0.925	—
$R_{cs}$	Saturation Resistance*	$V_{CB} = 5\text{V}$	$I_E = -1\text{mA}$	-0.953	—
		$I_B = 2.2\text{mA}$	$I_C = 5\text{mA}$	35	db
				20	db
				4	mc
				7	$\mu\text{uf}$
				100	Ohm
				200	

\*Common Emitter

† $R_g = 1\text{k}; R_L = 20\text{k}$ 

‡ Conventional Noise—Compared to 1000 ohm resistor, 1000 cps and 1 cycle band width

LICENSED UNDER BELL SYSTEM PATENTS

SEMICONDUCTOR-COMPONENTS DIVISION

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# TYPE 2N117

## TYPICAL CHARACTERISTICS

